

In-situ observation of symmetrical phase transition in MoSe₂ on graphene substrate

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Recently, tuning the electronic properties of atomically thin semi-conducting materials has become one of the exciting challenges. The modification of atomic structures by introducing ordered atomic defects has been demonstrated as a powerful strategy to control their band structures [1]. Inversion domain boundary (IDB) in transition metal selenides, such as MoSe₂, is one of the interesting ordered defect structures, which locally introduces 1D metallic channels in 2D atomic layers [2]. Understanding the mechanism of formation, elimination and migration of IDBs will be thus a key to control the electronic property of 2D layers.

In this work, we studied the formation and behavior of defect structures in MoSe₂ by *in-situ* aberration corrected transmission electron microscopy (AC-TEM) which enables simultaneous visualization and modification of atomic structure in 2D layers by electron irradiation. MoSe₂ monolayer grown on a CVD graphene was used in order to study the dynamics of MoSe₂ on the vdW substrate. First, the IDBs are successfully formed in a free-standing MoSe₂ monolayer (Figure 1) as previously observed in the literatures [3]. However the IDB formation was not observed in MoSe₂ supported on graphene but only the vacancy line (VL) defects are formed under the same condition (Figure 2) [4]. Although both the IDBs and VLs are Se deficient line defects, the formation of IDBs requires local symmetrical phase transition 2H to 2H'. The energy we supplied by the electron irradiation was not sufficient to promote a symmetrical phase transition in MoSe₂ layers on graphene substrate. We performed the *in situ* AC-TEM experiments at 400°C and 600°C using a dedicated heating sample holder to

trigger the symmetrical phase transition. In this presentation, we demonstrate direct observation of formation, migration and elimination of IDBs in MoSe₂ occurring on graphene surface at different conditions and their mechanisms will be discussed.

References

- [1] Lin et al., 2D Materials, 3 (2016) 022002
- [2] Barja et al., Nat., Phys., 12 (2016) 751
- [3] Lehtinen et al., ACS Nano, 3(2015)3274
- [4] C. Alvarez, H. Okuno et al., submitted.

Figures

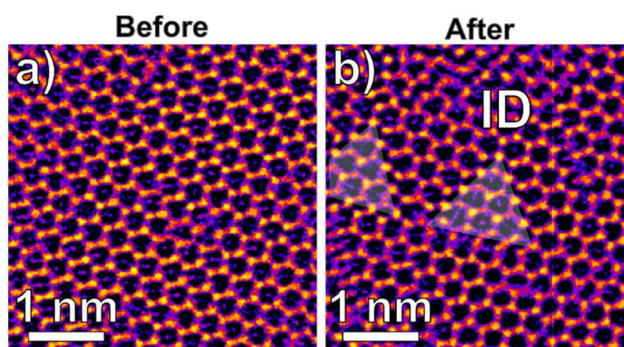


Figure 1: Inversion domain (ID) in free-standing MoSe₂ monolayer created after electron irradiation, following a local symmetrical phase transition.

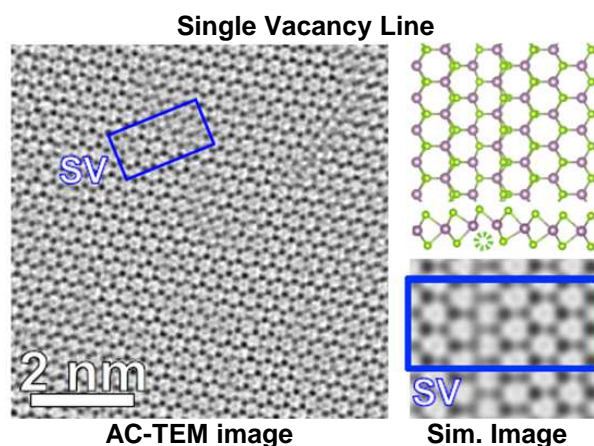


Figure 2: AC-TEM image with DFT model of single vacancy lines created in MoSe₂ monolayer on graphene substrate after the electron irradiation under the same condition as in Figure 1, whereas the vdW stacking of 2 monolayers was transferred together.